

# Search Notes



Application/Control No.

10/564,380

Examiner

Len Tran

Applicant(s)/Patent under Reexamination

DEIBL ET AL.

Art Unit

1725

## SEARCHED

Class	Subclass	Date	Examiner
164	448, 442, 427	3/17/2007	LT
EAST	update	8/23/07	KPK
EAST	citations	8/23/07	KPK
PLUS	search	8/23/07	KPK
EAST	keywords	8/23/07	KPK

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
164	448, 442, 427	8/23/07	KPK
interference search history		8/23/07	KPK

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Double Patenting search	3/17/2007	LT
update inventor search	8/23/07	KPK